

# VM316R

## 10-CHANNEL, CENTER-TAPPED FERRITE, THIN-FILM AND MIG HEAD READ/WRITE PREAMPLIFIER

**PRELIMINARY**

July, 1992

THREE TERMINAL  
READ/WRITE PREAMPS

### FEATURES

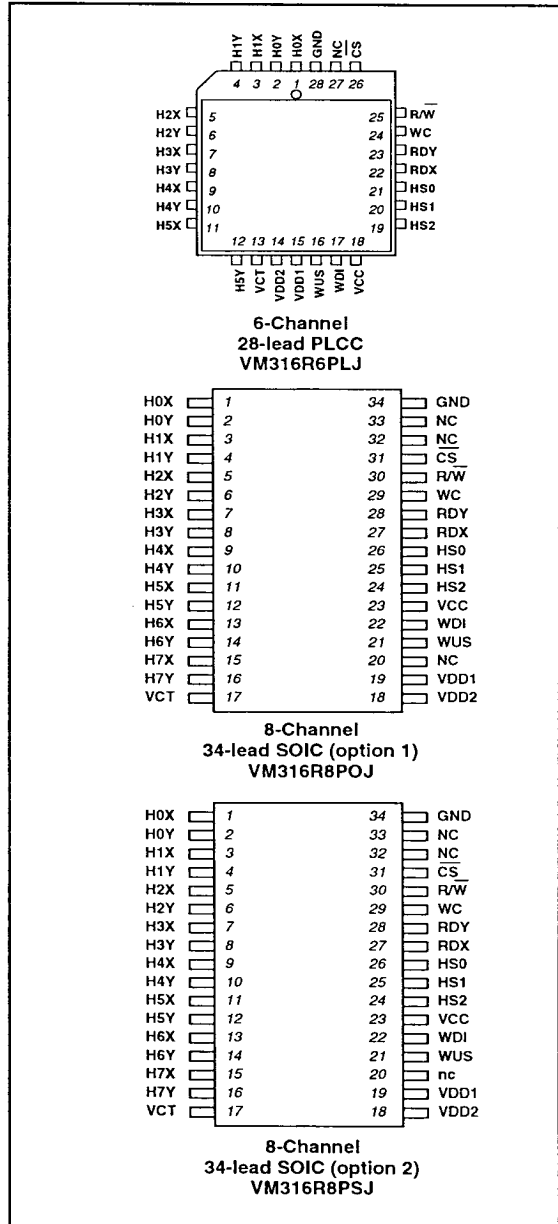
- High-Performance
  - Low Noise =  $0.75nV/\sqrt{Hz}$  typical
  - Input Capacitance = 11pF typical
  - Read Gain = 120V/V typical
  - Differential Head Swing = 24Vp-p minimum
  - $I_w$  Current Range = 10-90mA
- Power Supply Fault Protection
- Enhanced Write to Read Recovery Time
- For Use with Center-Tapped Ferrite or MIG Heads
- Write-Unsafe Detection Circuitry
- Pin Compatible with the VTC VM311
- Operates on +5V and +12V Power Supplies
- Up to 10 Channels Available

### DESCRIPTION

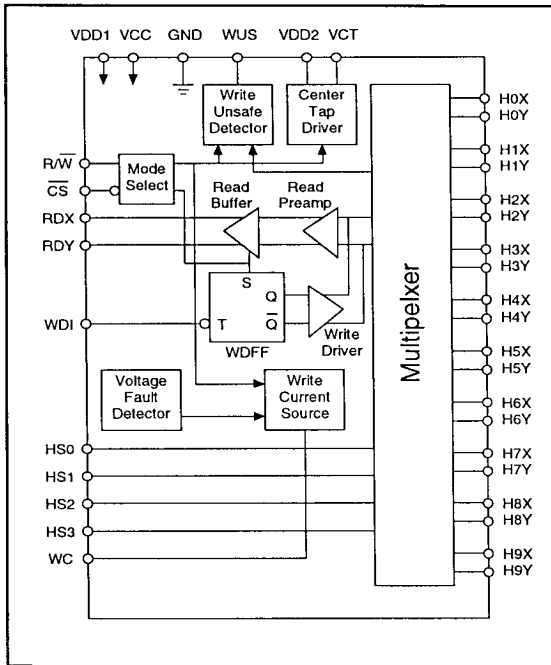
The VM316R is a bipolar, monolithic read/write preamp circuit, designed for use with up to ten center-tapped ferrite or MIG recording heads. The VM316R offers performance enhancements to the VM311R preamp circuit in noise and input capacitance in the read mode, and differential head voltage swing in the write mode. System write-to-read recovery is also improved by holding the RDX, RDY common mode outputs constant. The circuit provides a low noise read data path, write current control, write and power supply fault circuitry, and minimum power dissipation in the idle mode.

The VM316R is fabricated on VTC's high-performance complementary bipolar process. The circuit has a very fast mode and head select switching characteristics. The VM316R operates on +5V and +12V power supplies and is available in a variety of package options. Please consult factory for availability.

### CONNECTION DIAGRAMS



**BLOCK DIAGRAM**



THREE-TERMINAL HEAD/WRITE PREAMPS

**RECOMMENDED OPERATING CONDITIONS**

**DC Power Supply Voltage:**

V <sub>DD1</sub> .....	12V ± 10%
V <sub>DD2</sub> .....	10V to V <sub>DD1</sub>
V <sub>CC</sub> .....	5V ± 10%
Head Inductance (L <sub>H</sub> ) .....	1 to 15µH
Damping Resistance (R <sub>D</sub> on chip) .....	650Ω ± 20%
R <sub>CT</sub> Resistor (Note 1) (I <sub>W</sub> = 40mA) .....	130Ω
RDX, RDY Output Current (Read Mode) .....	0 to .5mA
Write Current Range .....	10 to 90mA
Operating Junction Temperature .....	25° to +125°C

Note 1: Resistor (R<sub>CT</sub>) used to limit power dissipation R<sub>CT</sub> (Ω) = 5.2/I<sub>W</sub>(A). Use of the R<sub>CT</sub> resistor may limit the differential voltage swing and increase write current rise times.

**CIRCUIT OPERATION**

The VM316R has three modes of operation: read, write and idle. In the read mode the circuit functions as a low-noise differential amplifier with selection of up to ten recording heads. In the write mode the circuit operates as a write current switch and provides write fault data protection. In the idle mode both the read amplifier and write driver are disabled and the power dissipation of the circuit is kept to a minimum. Mode selection is controlled by the R/W and CS TTL inputs as shown in Table 1. Both R/W and CS have internal pull-up resistors to prevent an accidental write condition. Head selection is controlled by the HS0, HS1, HS2 and HS3 TTL inputs as shown in Table 2. Each of the head select inputs have internal pull down resistors such that, if all head select inputs are open circuited, selection defaults to head zero.

**Write Mode**

The write mode configures the VM316R as a current switch and activates the write unsafe (WUS) detection circuitry. The head current is toggled between the X and Y side of a selected head on each high-to-low transitions on pin WDI (write data input). A preceding read operation initializes the write data flip-flop (WDF) so that upon entering the write mode current flows into the "X" head port.

The write current magnitude is determined by an external resistor connected between the WC pin and ground. An internally generated 2.5V reference voltage is present at the WC pin. The magnitude of the write current (0 - pk) is:

$$I_W = 2.5V/R_{WC}$$

In multiple-device applications, a single R<sub>WC</sub> resistor may be made common to all devices.

The write unsafe (WUS), open collector output, will give a high level for any of the following unsafe conditions:

- Open Head
- No Write Current
- Read/Idle Mode
- Write Data Frequency to Low
- Head Center-Tap Open

**ABSOLUTE MAXIMUM RATINGS**

**Power Supply:**

V <sub>DD1</sub> .....	-0.3 to +14V
V <sub>DD2</sub> .....	-0.3V to 14V
V <sub>CC</sub> .....	-0.3V to 6V

**Input Voltages:**

Head Select (HS) .....	-0.3V to V <sub>CC</sub> + 0.3V
Write Unsafe (WUS) .....	-0.3V to 10V
Write Data Input (WDI) .....	-0.3V to V <sub>CC</sub> + 0.3V
Chip Select .....	-0.3V to V <sub>CC</sub> + 0.3V
Read/Write Select (R/W) .....	-0.3V to V <sub>CC</sub> + 0.3V

**Output Current:**

Write Current (I <sub>W</sub> ) .....	120mA
Read Data (RDX, RDY) .....	10mA
Center Tap Current (I <sub>CT</sub> ) .....	120mA
Write Unsafe (WUS) .....	12mA

Operating Temperature Range .....	0° to 70°C
Storage Temperature Range .....	-65° to 150°C
Lead Temp. (Soldering 60 Seconds) .....	300°C

**Thermal Characteristics, Θ<sub>JA</sub>:**

Junction Temperature .....	150°C
34-Lead SOIC .....	60°C/W
36-Lead SOIC .....	60°C/W

After the fault condition is corrected, two negative transitions are required on WDI to clear the WUS line. The write unsafe circuitry allows a large inductance range and is not dependent on the magnitude of  $I_W$ . The VM316R will serve a wide range of head loads and write current values.

To further protect accidental writing to the disk, a voltage fault detection circuit ensures no write current during power loss or power sequencing. If either  $V_{CC} < 3.7$  or  $V_{DD} < 8.7V$ , the WC pin is clamped to ground and the write current source is disabled.

#### Read Mode

The read mode configures the VM316R as a low noise differential amplifier and deactivates the write current generator and write unsafe detection circuitry. The RDX and RDY outputs are emitter followers and are in phase with the "X" and "Y" head ports. These outputs should be AC coupled to the load. The RDX, RDY common-mode voltage is maintained in the write mode, minimizing the transient delay between write-to-read. Thermal offset effects are also minimized to enhance write-to-read recovery when doing a DC erase.

#### Idle Mode

In the idle mode ( $\overline{CS}$  = high level) both the read amplifier and write driver are disabled and the devices power dissipation is minimal. The RDX, RDY outputs are in a high impedance state and may be wire OR'ed for multiple chip usage to a common pulse detector circuit.

Table 1: Mode Select

$\overline{CS}$	$R/\overline{W}$	MODE
0	0	Write
0	1	Read
1	X	Idle

Table 2: Head Select

HS3	HS2	HS1	HS0	HEAD
0	0	0	0	0
0	0	0	1	1
0	0	1	0	2
0	0	1	1	3
0	1	0	0	4
0	1	0	1	5
0	1	1	0	6
0	1	1	1	7
1	0	0	0	8
1	0	0	1	9

#### PIN DESCRIPTIONS

NAME	I/O	DESCRIPTION
HS0-HS3	I	Head Select Inputs
$\overline{CS}$	I	Chip Select: a low level enables device
$R/\overline{W}$	I	Read/Write: a high level selects read mode
WUS	O	Write Unsafe: a high level indicates an unsafe writing condition
WDI	I	Write Data In: negative edge toggles the head current
H0X-H9X H0Y-H9Y	I/O	X,Y head connections
RDX, RDY	O	X,Y Read Data: differential read signal outputs
WC		Write Current: used to set the magnitude of the write current
VCT		Voltage Center Tap: voltage source for head center tap
VCC		+5 V
VDD1		+12 V
VDD2		Positive power supply for the center tap voltage source
GND		Ground

Table 3: External Resistor vs. Write Current

External resistor vs. DC write current $I_W$ into the selected head terminal X or Y with $V_{CT}$ shorted only to the respective X or Y terminal.	
External Resistor $R_{WC}$ ( $\Omega$ )	Write Current $I_W$ (mA)
249	10
124	20
82.5	30
61.9	40
49.9	50
41.2	60
35.7	70
30.9	80
27.4	90

Note: Effective current  $I_{FLUX}$  generated in the magnetic head is related to  $I_W$  by the expression:

$$I_{FLUX} = I_W \left( \frac{R_D}{R_H + R_D} \right)$$

Where  $R_H$  equals the full coil resistance of a center-tapped ferrite head and  $R_D$  is the damping resistor connected internally or externally between the X and Y terminals. Nominal internal resistance on VM316R is 650 $\Omega$ .

**DC CHARACTERISTICS** Unless otherwise specified, recommended operating conditions apply.

PARAMETER	SYM	CONDITIONS	MIN	TYP	MAX	UNITS
<b>POWER SUPPLY</b>						
Positive Supply Current	$I_{DD}$	Read Mode		20	27	mA
		Write Mode		$13 + I_W$	$17 + I_W$	
		Idle Mode		3.5	5	
	$I_{CC}$	Read Mode		19	26	mA
		Write Mode		17	21	
		Idle Mode		8	11	
Power Dissipation $T_J = 125^\circ\text{C}$ , $R_{WC} = 61.9\Omega$	$P_D$	Idle Mode		80	125	mW
		Read Mode		320	500	
		Write Mode $I_W = 40\text{mA}$ , $R_{CT} = 130\Omega$		500	600	
		Write Mode $I_W = 40\text{mA}$ , $R_{CT} = 0\Omega$		625	775	
<b>DIGITAL TTL INPUTS: CS, R/W, HS, WDI</b>						
Input High Voltage	$V_{IH}$		2		$V_{CC} + 0.3$	V
Input Low Voltage	$V_{IL}$		-0.3		0.8	V
Input High Current	$I_{IH}$	$V_{IH} = 2.0\text{V}$ , $V_{CC} = 5.5\text{V}$	-400		100	$\mu\text{A}$
Input Low Current	$I_{IL}$	$V_{IL} = 0.4\text{V}$ , $V_{CC} = 5.5\text{V}$	-400			$\mu\text{A}$
<b>WUS OUTPUT</b>						
Low Voltage	$V_{OL}$	$I_{OL} = 8\text{mA}$ (Safe)			0.5	V
High Current	$I_{OH}$	$V_{OH} = 5\text{V}$ (Unsafe)			100	$\mu\text{A}$

**READ CHARACTERISTICS** Unless otherwise specified, recommended operating conditions apply.

PARAMETER	SYM	CONDITIONS	MIN	TYP	MAX	UNITS
Differential Voltage Gain	$A_V$	$V_{IN} = 1\text{mVpp}$ , @ 1MHz $R_L (RDX, RDY) = 1\text{K}\Omega$	100		140	V/V
Dynamic Range	DR	DC Input Voltage where AC Gain Falls 10%, $V_{IN} = V_i + 0.5\text{mVp-p}$ @ 1MHz	-2		+2	mV
Bandwidth (-3 dB)	BW	$V_{IN} = 1\text{mVpp}$ , $Z_S < 5\Omega$	30			MHz
Input Noise Voltage	$e_{in}$	$L_H = 0$ , BW = 15MHz		0.75	1.0	$\text{nV}/\sqrt{\text{Hz}}$
Differential Input Capacitance	$C_{IN}$	f = 5MHz		11	15	pF
Differential Input Resistance	$R_{IN}$	VM316R, f = 5MHz	400		800	$\Omega$
Common Mode Rejection Ratio	CMRR	$V_{CM} = V_{CT} + 100\text{mVp-p}$ , @ 5MHz	50			dB
Power Supply Rejection Ratio	PSRR	100mVpp @ 5MHz, on $V_{DD1}$ , $V_{DD2}$ or $V_{CC}$	45			dB
Channel Separation	CS	Unselected Channels: $V_{IN} = 100\text{mVpp}$ @ 5MHz $V_{IN} = 0$ on Selected Head	45			dB
Single-Ended Output Resistance	$R_{OUT}$	f = 5MHz			30	$\Omega$
Output Load Current	$I_{OUT}$	AC Coupled Load, RDX to RDY	2.1			mA
Center-Tap Voltage	$V_{CT}$	Read/Idle Mode		4.2		V
RDX, RDY Output Offset Voltage	$V_{OS}$	Read Mode	-300		+300	mV
RDX, RDY Output Common Mode Voltage	$V_{CM}$	Read Mode	2.0		3.0	V
Input Current (per side)	$I_H$				65	$\mu\text{A}$
Head Current (per side)	$I_H$	$V_{CC} < 3.7\text{V}$ , $V_{DD} < 8.7\text{V}$	-0.2		+0.2	mA

VM316R

**WRITE CHARACTERISTICS** Unless otherwise specified, recommended operating conditions apply.

PARAMETER	SYM	CONDITIONS	MIN	TYP	MAX	UNITS
Write Current Range	$I_W$	(See table 3)	10		90	mA
Write Current Tolerance	$\Delta I_W$	Over $I_W$ range	-8		+8	%
Differential Head Voltage	$V_{DH}$		12			Vpk
Current Gain	$A_I$			.99		mA/mA
Unselected Head Current	$I_{UH}$	@ $I_W = 40\text{mA}$			2	mA p-p
Head Current Propagation Delay	$t_{PD}$	$L_H = 0\mu\text{H}$ , $R_H = 0$ , 50% WDI to 50% $I_W$		15	30	ns
Rise/Fall Time	$t_r$ , $t_f$	$L_H = 0\mu\text{H}$ , $R_H = 0$ , 10% to 90%		3	10	ns
Asymmetry	$A_S$	WDI has 50% duty cycle and 1ns rise/fall times		0.1	1	ns
Differential Output Resistance	$R_{OUT}$	VM316R	500		900	$\Omega$
Differential Output Capacitance	$C_{OUT}$	$f = 5\text{MHz}$			15	pF
WDI Transition Frequency	$f_{min}$		1.25			MHz
Center Tap Voltage	$V_{CT}$			10		V
Head Current (per side)	$I_H$	$V_{CC} < 3.7\text{V}$ ; $V_{DD} < 8.7\text{V}$	-0.2		+0.2	mA
RDX,RDY Output Offset Voltage	$V_{OS}$		-30		+30	mV
RDX, RDY Common Mode Output Voltage	$V_{CM}$	$L_H = 0\mu\text{H}$ , $R_H = 0$ , 50% WDI to 50% $I_W$ , (Write or Idle Mode)		2.5		V
RDX, RDY Leakage	$I_L$	RDX, RDY = 5V, (Write or Idle Mode)			100	$\mu\text{A}$
Unselected Leakage Current	$I_{UH}$				85	$\mu\text{A}$

**SWITCHING CHARACTERISTICS** Unless otherwise specified, recommended operating conditions apply.

PARAMETER	SYM	CONDITIONS	MIN	TYP	MAX	UNITS
Read-to-Write Switching Delay	$t_{RW}$	50% of R/W to 90% of Write Output Envelope			500	ns
Write-to-Read Switching Delay	$t_{WR}$	50% of R/W to 90% of 100mVp-p Read Envelope (RDX, RDY)			500	ns
Idle-to-Write Switching Delay	$t_{IW}$	50% of CS to 90% of Write Current			500	ns
Idle-to-Read Switching Delay	$t_{IR}$	50% of CS to 90% of 100mVp-p Read Envelope (RDX, RDY)			500	ns
Write-to-Idle Switching Delay	$t_{WI}$	50% of CS to 10% of Write Current			500	ns
Read-to-Idle Switching Delay	$t_{RI}$	50% of CS to 10% of Read Envelope			500	ns
Head Select Switching Delay	$t_{HS}$	50% of HS to 90% of 100mVp-p Read Envelope (RDX, RDY)			500	ns
WUS Delay Safe-to-Unsafe	$t_{D1}$	$L_H = 10\mu\text{H}$ , $I_W = 10 - 90\text{mA}$	1.6		8	$\mu\text{s}$
WUS Delay Unsafe-to-Safe	$t_{D2}$	$L_H = 10\mu\text{H}$ , $I_W = 10 - 90\text{mA}$			1	$\mu\text{s}$